

Application Serial No. 10/632,273
Examiner Interview Summary

MI22-2379

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 10/632,273
Filing Date July 31, 2003
Inventor Warren M. Farnworth et al.
Assignee Micron Technology, Inc.
Group Art Unit 2829
Examiner R. Kobert
Attorney's Docket No. MI22-2379
Customer No. 021567

Title: Method and Apparatus for Testing Semiconductor Circuitry for Operability
and Method of Forming Apparatus for Testing Semiconductor Circuitry for
Operability

EXAMINER INTERVIEW SUMMARY OF JANUARY 4, 2005

To: Commissioner for Patents Via Facsimile 1-571-273-1963
Washington, D.C. 20231

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Applicant's representative held an interview with Examiner Kobert on January 4, 2005. Applicant's representative would like to thank Examiner Kobert for his time and attention to this matter.

No agreement was reached. The Office Action Response dated December 7, 2004, was discussed, particularly, the amendments to the claims. For example, as amended, the Examiner states independent claim 31 recites a

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patently distinct invention from the invention recited before the amendment. Applicant requested the Examiner provide such argument in an Office Action for further consideration.

Applicant would like to again thank Examiner Kobert for his time and attention to this matter.

Respectfully submitted,

Dated: 1-4-05

By: 
D. Brent Kenady
Reg. No. 40,045